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Patents 1 - 1 on **fault transient power abnormality test pattern**. (0.04 seconds)

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[System to assess the starting performance of a turbine](#)

US Pat. 5748500 - Filed Nov 14, 1995 - Electric Power Research Institute, Inc.

The risk matrix output for each specific shutdown **fault** points to those risks ... Speed **transient** at light-off 5. Speed reference versus measured speed 6. ...

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Dynamic burn-in test equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

And the difference **current flows** in the **test pattern generator** ...
Therefore, when the currents flowing in the higher level **power supply** lines and

...

Transient test of suspension electronics for gyroscope

US Pat. 4654582 - Filed Jul 8, 1985 - The United States of America as represented by the Secretary of the Air Force

10 shows the sensor 1042 of the high voltage **power supply** 16. ...
functional

electronic subdivisions of the suspension system for signal **abnormality**, ...

Load protection circuit

US Pat. 5055703 - Filed Feb 13, 1990 - Perma Power Electronics, Inc.

15 16 **power supply** 2, which in turn constantly powers an inverter 3. ... In the event of **power line abnormality**, the phase detector and control circuit CC ...

Standby power supply

US Pat. 4956563 - Filed Nov 9, 1987 - Perma Power Electronics, Inc.

In the event of **power line abnormality**, the phase acting circuit breaker which

does not **supply** an alterna- detector and control circuit CC acts on the ...

Modular power quality monitoring device

US Pat. 6404348 - Filed Mar 23, 1999 - Power Quality Consultants, Inc.

The detectable electrical phenomenon includes SPD/ PQE status, voltage levels,

current draw, **power surges**, phase outages, phase shifting, **power factor**, ...

Semiconductor integrated circuit having therein circuit for detecting ...

US Pat. 5343479 - Filed Oct 31, 1990 - NEC Corporation

In this spec- level signal **abnormality** detection circuits, ... creased impedance

of a voltage **supply** line of a **test** 50 *he/rst Concentrating circuit so ...

Steering stabilizing method and apparatus for suppressing the weave mode

US Pat. 4951199 - Filed Nov 16, 1987

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Integrated circuit **test power supply**

US Pat. 5773990 - Filed Sep 29, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ...

transient accumulated charge, and the device under **test power supply** 102 is set

...

Quiescent **power supply current test** method and apparatus for integrated ...

US Pat. 5731790 - Filed Jun 19, 1996 - LSI Logic Corporation

For example, a particular More specifically, the quiescent **power supply current**

test pattern can be stored in a memory device, and then read IDDQ is sensed ...

Integrated circuit fault testing system based on **power** spectrum analysis of ...

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

20 ing a **test pattern** to the CMOS integrated circuit under **test**: FIG. shows ...

4' under **test** deriving a **power** spectrum of the **supply current** detected by to ...

Semiconductor integrated circuit fault analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

Upon completion of setting the conditions, the ON/OFF control means 3a turns on

the **power supply** for the DUT 8 (step S204), and a designated **test pattern** is ...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

The quiescent **power supply current test** is a procedure which assumes a ... 1997;

and for **transient power supply current test**, a description is given, ...

Apparatus for reducing **power supply** noise in an integrated circuit

US Pat. 6339338 - Filed Jan 18, 2000 - Formfactor, Inc.

Power control 1C 52 includes a **pattern** generator 54 that carries out the **pattern**



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Integrated circuit fault testing system based on power spectrum analysis of ...

US Pat. 5949788 - Filed Feb 4, 1997 - NEC Corporation

20 ing a **test pattern** to the CMOS integrated circuit under **test**: FIG.

shows ...

4' under **test** deriving a **power** spectrum of the **supply current** detected by to ...

Method and apparatus for testing semiconductor integrated circuits

US Pat. 5760599 - Filed Aug 6, 1996 - Sharp Kabushiki Kaisha

In the CMOS, since a **transient current** with larger difference at both ends.

...

changes of the **power** source **current** due to the **test pattern**. a^hso detected, ...

Method for the continuous flow make of customized planar electrical circuits

US Pat. 4935093 - Filed Feb 11, 1988

Via line 704, the result of the **current** state of etching measurement is ... duty

cycle of a suitable polarizing **power supply** for providing said **current**. ...

Automated computerized magnetic resonance detector and analyzer

US Pat. 5592086 - Filed Oct 19, 1994

a tuned curcuit and a series of chokes to isolate the **power supply** from the output circuit. ... The output of the modulator 16 is a **test pattern** signal 21,

...

Computer and electromagnetic energy based mass production method for the ...

US Pat. 5294290 - Filed Sep 30, 1992

Via line 704, the result of the **current** state of '0 forms well for obtaining a fast ... polarizing **power supply** for providing said speed process conditions.

...

A DC power supply controller

US Pat. 5656923 - Filed Apr 10, 1995 - The Whitaker Corporation

(9) switching **pattern** of the transistor 162, but the **current** loop of the ...

with a load more complex than microcontroller **power** and time. a resistor. ...

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Integrated circuit fault testing implementing voltage **supply** rail pulsing ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple **current** mirror detected the **transient current** (IDD) while

...

Fault location methods and apparatus using **current pulse** injection

US Pat. 4377782 - Filed Jun 20, 1980 - Membrain Limited

via the bus 202, with its required **power** supplies and a sequence of test ... **transient** faults, since it ensures that the **fault** locating **current pulse** is ...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

Accordingly, the quiescent **power supply current** test is very difficult to perform ... **fault** test, the 60 functional test, the exhaustive test, the **transient ...**

Power line fault detector and analyzer

US Pat. 6798211 - Filed Oct 29, 1998 - Remote Monitoring Systems, Inc.

6 to determine the **location** of the **fault**. The only difference is that the ... to detect a **transient** signal representing a **fault**; and a **power supply**, ...

Multiprocessor for providing fault isolation test upon itself

US Pat. 4181940 - Filed Feb 28, 1978 - Westinghouse Electric Corp.

With the resumption of normal **power supply** conditions, processors 10 and 12 ...

to isolate the **location** of a processor **fault** capable of causing said error; ...

Method and apparatus for locating resistive faults in communication and ...

US Pat. 5990686 - Filed Jun 18, 1996

1 is a graph showing the **transient** voltage conditions at the end of a long conductor; ... is closed to connect the **power supply** 16a to the conductor 10.

...

System and method for locating faults in electric power cables

US Pat. 5682100 - Filed Sep 6, 1995 - Electric Power Research Institute Inc.

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Arrangement for **transient-current** testing of a digital electronic CMOS circuit

US Pat. 6414511 - Filed Feb 7, 2000 - Koninklijke Philips Electronics N.V.
Generally, **transient-current** measurements or so-called IDDT ... "Defect Detection with **Transient Current** Testing and its Potential for Deep Sub-micron CMOS ...


Method and apparatus for testing an integrated circuit with a pulsed ...

US Pat. 6169408 - Filed Sep 30, 1996 - Motorola, Inc.
10, the IDDT **current** spikes of Node A are filtered as taught herein.

However, the node C waveform of FIG. 10 illustrates the noise injected into ...

Power converter

US Pat. 4410936 - Filed Jan 18, 1982 - Oki Electric Industry Co., Ltd.
Thus, the decrease of the value $i_{...}$ increases the **current** in the diode 5, ... the present invention decreases the power loss in the switching **transient** in ...

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CMOS integrated circuit failure diagnosis apparatus and diagnostic method

US Pat. 5790585 - Filed Jan 13, 1997 - NEC Corporation

... a CMOS integrated all the patterns at which an lddq **abnormality** is not ...

under test (DDT) 4 correspond- More specifically, from the results of a ...

Integrated circuit early life failure detection by monitoring changes in ...

US Pat. 6714032 - Filed Apr 25, 2000 - Agere System inc.

40 present invention includes an apparatus for **testing** integrated Methods for

... measuring a current signature delta value of the integrated \ddt, **testing**.
...

Daphnia reproductive bioassay for **testing** toxicity of aqueous samples and ...

US Pat. 6150126 - Filed Sep 16, 1998 - Wisconsin Alumni Research Foundation

... for example, **abnormal** swimming behavior, and **abnormal** motility. ...
chlorpyrifos, pentachlorophenol (PCP), and dichlorodiphenyl-trichloroethane (DDT)
); ...

Environmental stress screening apparatus for electronic products

US Pat. 4949031 - Filed Apr 5, 1988 - General Signal Corporation

Conventional The present invention relates to apparatus for **testing** ...
abnormal
or marginal parts hi manufac- environmental chambers and thus the ...

CERTAIN THIADIAZOLES AS FUNGICIDES

US Pat. 3764685 - Filed Sep 8, 1970

... tissue or the EXAMPLE 7 development of galls and other **abnormal** growths. ...

for example: DDT, methoxy- 40 tol of 100 percent for both types of fungus,
...

HALO-L,Z,X-THIADIAZOLES

US Pat. 3720684 - Filed Oct 13, 1970

The results of the test were as follows: compounds, for example: DDT, methoxychlor, TDE, lindane, chlordane, ...

Vascular endothelial growth factor C (VEGF

DDT testing abnormal OR abnormality OR ar

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Integrated circuit fault testing implementing voltage **supply** rail pulsing ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple current mirror detected the **transient current** (IDD) while

...

Fast recovery power supply

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

Because capacitor 35 now recharges quickly the satu- **transient current** and quickly ... Thus, fast recovery **power supply**, the output 37 provides a measurable ...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

The quiescent **power supply** current test is a procedure which assumes a ...

Defect Detection with **Transient Current Testing** 35 and its Potential for Deep

...

Automatic controlled for an ice and snow melting system with ground fault ...

US Pat. 5710408 - Filed Aug 15, 1996 - MSX, Inc.

The heater 14 **supply** leads are 35 Operating the switch 98 causes the test current to ... **transient current** flow that may occur upon application the two line ...

Built-in test circuit for static CMOS circuits

US Pat. 5097206 - Filed Oct 5, 1990 - Hewlett-Packard Company
power path between the **supply** voltage and the row The circuitry described ...

invention a voltage sensor that produces **fault** indicator signal includes, ...

Rapid transit system transient voltage suppression apparatus

US Pat. 4322772 - Filed Mar 21, 1980 - Westinghouse Electric Corp.

Therefore, for a given **fault** current condition and a given **power supply** ... of **transient current** within 10 milliseconds, as shown by curve 264 of FIG. 11.

...

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